ALLION®
Engineering Services

COMPLIANCE PROGRAM
TEST REPORT

USB 2.0 Test Report
For
Embedded Host Revision 2.0

Company Name: Freescale Semiconductor

VID (Dec or Hex): 15A2 The VID for the company who apply the USB-IF logo.

Model Name: i.MX6UL

Product Type: Embedded Host with Device Mode

Report Date: 2015/08/26

Test Result: **PASS**

Tester: **Mild Yang**   Authorized Signature: *Howard Chang*

Legal Disclaimer

1. TEST RESULT IS VALID ONLY TO THE ORIGINAL TESTED DEVICE MODEL. ALLION RESERVES THE RIGHT TO PROHIBIT OTHERS TO DISTORT, ISOLATE, FALSIFY, COPIED AND/OR BY ANY PROCESS TO CHANGE THE CONTENT OF THIS TEST REPORT UNLESS IT IS PRIOR APPROVED BY ALLION.

Company Information:

Company
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Product Information:

Information Obtained From Checklist or Vendor			
Input	**Type**	**Purpose**	**Checklist Ref**
Uses Micro-AB	☐	**Check this box for an EH which uses a Micro-AB receptacle instead of a Standard-A receptacle. It will be automatically selected for OTG devices.**	**P15a**
Supports Sessions	☐	**Check this box if the OTG A-UUT or EH with Micro-AB receptacle does not keep V BUS enabled all the time that the ID pin is held low. Check this box for an EH with Standard-A receptacle which does not keep V BUS high all the time it is powered up. In either case it is assumed that SRP or ADP is available to detect the presence of a device.**	**PI10**

Input	Type	Purpose	Checklist Ref
SRP as A-device	☐	**Check this box if the UUT, as an A-device, supports detecting, and acting on, an SRP pulse generated by a connected device.**	**PI13**
HNP as A-device	☐	**Check this box if the UUT, as an A-device, supports HNP to enable the connected B-device to become host if it so requires.**	**PI13**
HNP Polling as A-device	☐	**Check this box if the UUT, as an A-device, supports HNP polling. If it does it is allowed to remain as host, for as long as the other device does not set its Host Request Flag.**	**PI13**
ADP as A-device	☐	**Check this box if the UUT, as an A-device, supports ADP probing to detect the presence or otherwise of a connected device.**	**PI13**
SRP as B-device	☐	**Check this box if the UUT, as a B-device, supports generating an SRP pulse in order to start a session (cause the connected A-device to turn on V BUS).**	**PI20**
HNP as B-device	☐	**Check this box if the UUT, as an B-device, supports HNP to allow it to become host if it so requires.**	**PI20**
ADP as B-device	☐	**Check this box if the UUT, as an B-device, supports ADP sensing and probing to detect the presence or otherwise of a connected device.**	**PI20**
FS Not Available	☐	**Check this box if UUT does not fully support full-speed operation. This is not permitted for an OTG device, but may be for an Embedded Host.**	**PI11, PI18**

Input	Type	Purpose	Checklist Ref
$I_{A\_VBUS\_RATED}$	<u>500</u> mA	The rated output current of an A-device in mA units.	PI8
bMaxPower	____ mA	bMaxPower (sic) is the highest current, in mA, declared in any of the device's Configuration Descriptors. This value ignores current drawn under the Battery Charging provisions.	PI17
TPWRUP_RDY	<u>30 S</u>	Maximum time, in seconds, specified by vendor from powering on the UUT until it is ready to perform USB functionality. By default this is set to 30 seconds, but a vendor is permitted to specify a longer time.	PI24
TA_WAIT_BCON max	____ S	The maximum time, in seconds, that V BUS is left on for by an A-device, in the absence of a B-device connecting. The default value is thirty seconds. A vendor is permitted to specify a longer time, but should be aware that this will have an impact on the time taken for, and therefore possibly the cost of, compliance testing.	PI10
Unknown Dev (No HNP)	<u>VID:</u> <u>1A0A</u> <u>PID:</u> <u>0201</u>	The test will use the VID/PID combination specified during tests for error messages, when an unknown B-device, not capable of HNP, is connected. A default value (1A0A/0201) is used, but any other device not on the UUT's TPL may be defined here.	-

Input	Type	Purpose	Checklist Ref
Unknown Dev (HNP)	VID: 1A0A PID: 0202	The test will use the VID/PID combination specified during tests for error messages, when an unknown B-device, capable of HNP, is connected. A default value (1A0A/0202) is used, but any other device not on the UUT's TPL may be defined here.	-

Test Cable Information:

Information Obtained From Checklist or Vendor			
Input	**Type**	**Purpose**	
Cable A	211 mΩ	Test Cable A loop resistance in mΩ.	
Cable B	572 mΩ	Test Cable B loop resistance in mΩ.	

Project ID：EBH-FRC-USB-002
Document Number：AR-TRL011413

High Speed & Basic Speed Compliance Tests

A4.4: Host High-speed Signal Quality   ☒ Pass   ☐ Fail   ☐ N/A

These tests measure the ability of transmitters to do valid high speed signaling. High speed signal quality is measured on upstream ports. A high speed scope with differential probes is used. Signaling data is captured with the scope and then translated to an eye pattern. The signal quality eye patterns obtained from the measurements must agree with the transmit eye patterns in the USB 2.0 Specification.

Port	01
EL_2: Data Rate	Pass
EL_3: Eye Pattern	Pass
EL_6: Rise and Fall Time	Pass
EL_7: Monotonic	Pass

A4.5: Host Controller Packet Parameters   ☒ Pass   ☐ Fail   ☐ N/A

This test measures the amount of time it takes hosts and devices to respond. It also verifies Host generated SYNCs and EOPs.

EL_21: (32bit)	32bit/32bit	☒ Pass	☐ Fail	☐ N/A
EL_25: (8bit)	8bit	☒ Pass	☐ Fail	☐ N/A
EL_23: (>=88bit and <=192bit)	158bit	☒ Pass	☐ Fail	☐ N/A
EL_22: (>=8bit and <=192bit)	127bit	☒ Pass	☐ Fail	☐ N/A
EL_55: (40bit)	40bit	☒ Pass	☐ Fail	☐ N/A

A4.7: Host CHIRP Timing   ☒ Pass   ☐ Fail   ☐ N/A

This test examines the basic timings and voltages of both upstream ports during the speed detection protocol. (Device reset from Full Speed)

EL_33: (<=100us)	1.2us	☒ Pass	☐ Fail	☐ N/A
EL_34: (>=40us and <=60us)	50us	☒ Pass	☐ Fail	☐ N/A
EL_35: (>=100us and <=500us)	348us	☒ Pass	☐ Fail	☐ N/A

A4.8: Host Suspend/Resume/Reset timing ☐ **Pass**   ☐ **Fail**   ☒ **N/A**

This test verifies that a Host can be suspended and resumed while operating in high speed and also that the device can be reset from the suspended state.

EL_39:	☐ **Pass**	☐ **Fail**	☒ **N/A**
EL_41: (<=3ms) us	☐ **Pass**	☐ **Fail**	☒ **N/A**

A4.9: Host Test J/K, SE0_NAK (EL_9) ☒ **Pass**   ☐ **Fail**   ☐ **N/A**

The USB-IF no longer requires EL_8: Test_J and Test_K to be performed as a condition for USB Certification. Measurement of EL_9: Test_J, Test_K and SE0 is still a requirement for certification. EL_9 is defined in the USB 2.0 Test Specification and measures the data line voltage when not driven. For detail information please reference as below link:

EL_9

Port	01
SE0_NAK D+	1.0
SE0_NAK D-	1.1
Test J D-	7.0
Test K D+	7.1

(-20mV to 20mV)

Basic Speed Signal Quality Test Result ☒ **Pass**   ☐ **Fail**   ☐ **N/A**

Full Speed Downstream Signal Quality: ☒ **Pass**   ☐ **Fail**   ☐ **N/A**

Port 01
Pass

Low Speed Downstream Signal Quality: ☒ **Pass**   ☐ **Fail**

Port 01
Pass

Project ID：EBH-FRC-USB-002
Document Number：AR-TRL011413

Drop/ Droop Test Result   ☒ **Pass**   ☐ **Fail**

500mA

Port	01
$V_{non\text{-}load}$ **(>=4.75V and <=5.50V)**	**5.187V**
V_{load} **(>=4.75V and <=5.50V)**	**4.874V**
V_{drop} **(<=750mV)**	**313mV**
V_{droop} **(<=330mV)**	**N/AmV**

BC 1.2 Implemented Check: ☐ **Support** ☒ **N/A**

If any one of exposed ports has BC 1.2 capability, all items of BC 1.2 specific category(s) should be tested under this port(s) for USB-IF certification.

Port 01
N/A

Project ID：EBH-FRC-USB-002
Document Number：AR-TRL011413

Embedded Host PET Automated Test (CH 6)

A-UUT

Test Item	Result
6.7.2 A-UUT Initial Power-up Test	Pass
6.7.4 A-UUT V_{BUS} Voltage and Current Measurements	Pass
6.7.5 A-UUT Bypass Capacitance	Pass
6.7.6 A-UUT SRP	Pass
6.7.8 A-UUT ADP	Pass
6.7.9 A-UUT Leakage	Pass
6.7.14 EH, Capable of ADP and SRP, State Transition Test (Standard-A)	N/A
6.7.15 EH, Capable of ADP but not SRP, State Transition Test (Standard-A)	N/A
6.7.16 EH, Capable of SRP but not ADP, State Transition Test (Standard-A)	N/A
6.7.17 EH with no Session Support State Transition Test (Standard-A)	Pass
6.7.18 EH, Capable of ADP and SRP, (Micro-AB) or OTG-A , Capable of ADP and SRP but not HNP, State Transition Test	N/A
6.7.19 EH, Capable of ADP but not SRP, (Micro-AB) or OTG-A , Capable of ADP but not SRP or HNP, State Transition Test	N/A
6.7.20 EH, Capable of SRP but not ADP, (Micro-AB) or OTG-A , Capable of SRP but not ADP or HNP, State Transition Test	N/A
6.7.21 EH with no Session Support State Transition Test (Micro-AB), or OTG-A with no Session or HNP Support	N/A
6.7.22 A-UUT "Device No Response" for connection timeout	Pass
6.7.23 A-UUT "Unsupported Device" Message	Pass
6.7.24 A-UUT "Device No Response" for HNP enable	N/A
6.7.25 EH using Micro-AB "Incorrect Connection"	N/A

B-UUT

Only tested when Embedded Host B-Port is applied

Test Item	Result
6.8.1 B-UUT Initial Power-up Test	N/A
6.8.2 B-UUT V_{BUS} Voltage and Current Measurements	N/A
6.8.3 B-UUT Bypass Capacitance	N/A
6.8.4 B-UUT SRP	N/A
6.8.6 B-UUT ADP	N/A
6.8.7 B-UUT Leakage	N/A
6.8.16 B-UUT "Device no response" for SRP	N/A

Project ID：EBH-FRC-USB-002
Document Number：AR-TRL011413

Embedded Host Manual Interoperability Tests (CH 7)

This section will perform DUT interoperability with peripheral that on the vendor's Target Peripheral List.

Test Item	Result
7.3.1 A-UUT Functionality B-device	N/A
7.3.2 A-UUT Category Functionality B-device	Pass
7.3.3 A-UUT Boot test	Pass
7.3.4 A-UUT Legacy Speed test	Pass
7.3.5 A-UUT Concurrent and Independently test	N/A
7.3.6 A-UUT Unsupported device Message test	Pass
7.3.7 A-UUT Hub Error message test	N/A
7.3.8 A-UUT Hub Functionality test	Pass
7.3.9 A-UUT Hub maximum tier test	Pass
7.3.10 A-UUT Hub Concurrent and Independent test	Pass
7.3.11 A-UUT Bus powered hub power exceeded test	Pass
7.3.12 A-UUT Maximum concurrently device exceed message test	N/A
7.3.13 A-UUT Standby test	N/A
7.3.14 A-UUT Standby Disconnect test	N/A
7.3.15 A-UUT Standby Attach test	N/A
7.3.16 A-UUT Standby Topology Change test	N/A
7.3.17 A-UUT Standby Remote Wakeup test	N/A

Project ID：EBH-FRC-USB-002
Document Number：AR-TRL011413

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Battery Charging 1.2 Compliance Test

Dedicated Charging Port (DCP) ☐ **Pass**   ☐ **Fail**   ☒ **N/A**

Port / Test Items	Port 01	Port 02	Port 03	Port 04
DCP Overshoot and Undershoot Voltage Test				
DCP Handshaking Test				
DCP Resistance and Capacitance Tests				
DCP Voltage and Current				

Charging Downstream Port (CDP) ☐ **Pass**   ☐ **Fail**   ☒ **N/A**

Port / Test Items	Port 01	Port 02	Port 03	Port 04
CDP Overshoot and Undershoot Voltage Test				
CDP Voltage and Current Test				
CDP Handshaking Test				
CDP Ground Offset Test – Full Speed				
CDP Ground Offset Test – High Speed				

Standard Downstream Port (SDP) ☐ **Pass**   ☐ **Fail**   ☒ **N/A**

Port / Test Items	Port 01	Port 02	Port 03	Port 04
SDP Handshaking Test				

Project ID：EBH-FRC-USB-002
Document Number：AR-TRL011413

Multiple Role Port (MRP)   ☐ Pass   ☐ **Fail**   ☒ N/A

Test Items / Port	Port 01	Port 02	Port 03	Port 04
MRP Functional Test				

Project ID：EBH-FRC-USB-002
Document Number：AR-TRL011413

More Detail Test Result:
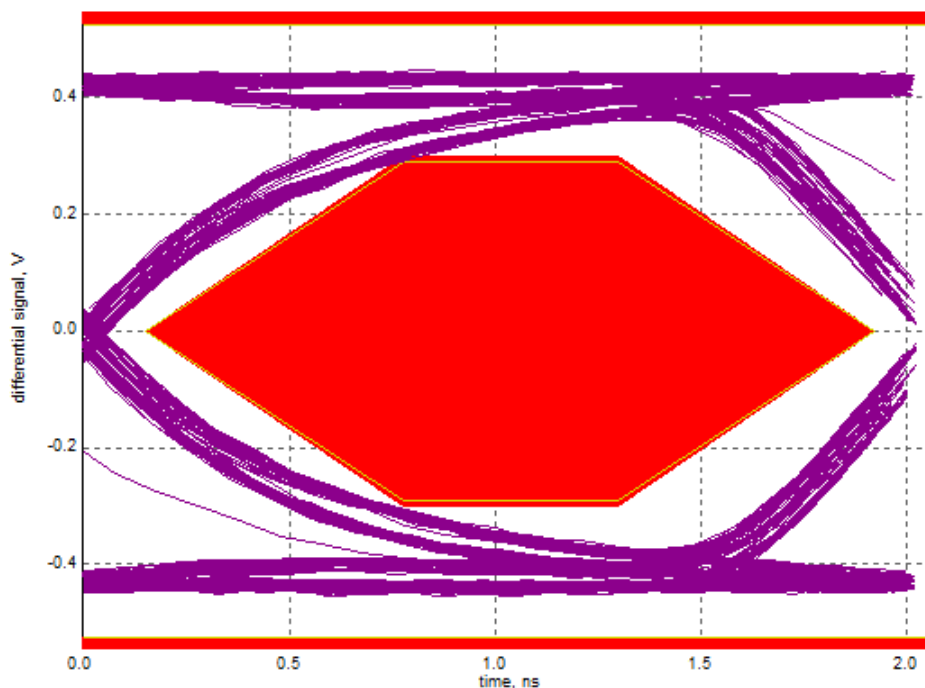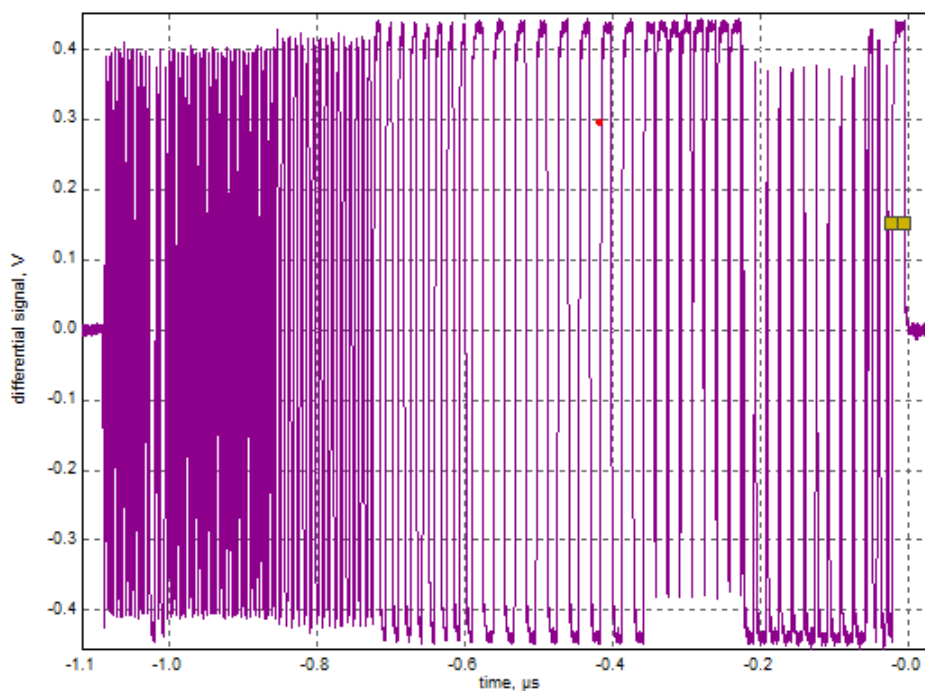
1. High Speed Downstream Signal Quality: Pass

- Overall result: pass!
- Sync result:
  sync passes
- Signal eye:
  *** eye failure! *** (1 data point violates eye)
  *** last transition exception invoked ***

- EOP width: 7.95 bits
  EOP width passes
- Measured signaling rate: 480.0068 MHz
  signal rate passes
- Edge Monotonicity: 0 mV
  Monotonic Edge passes
- Rising Edge Rate: 702.97 V/us (910.42 ps equivalent risetime)
  passes
- Falling Edge Rate: 712.36 V/us (898.42 ps equivalent falltime)
  passes

Additional Information

- Consecutive jitter range: -55.938 ps to 66.896 ps, RMS jitter 33.073 ps
- Paired JK jitter range: -76.198 ps to 56.907 ps, RMS jitter 15.068 ps
- Paired KJ jitter range: -62.785 ps to 49.941 ps, RMS jitter 12.954 ps

SignalData and Eye

Project ID：EBH-FRC-USB-002
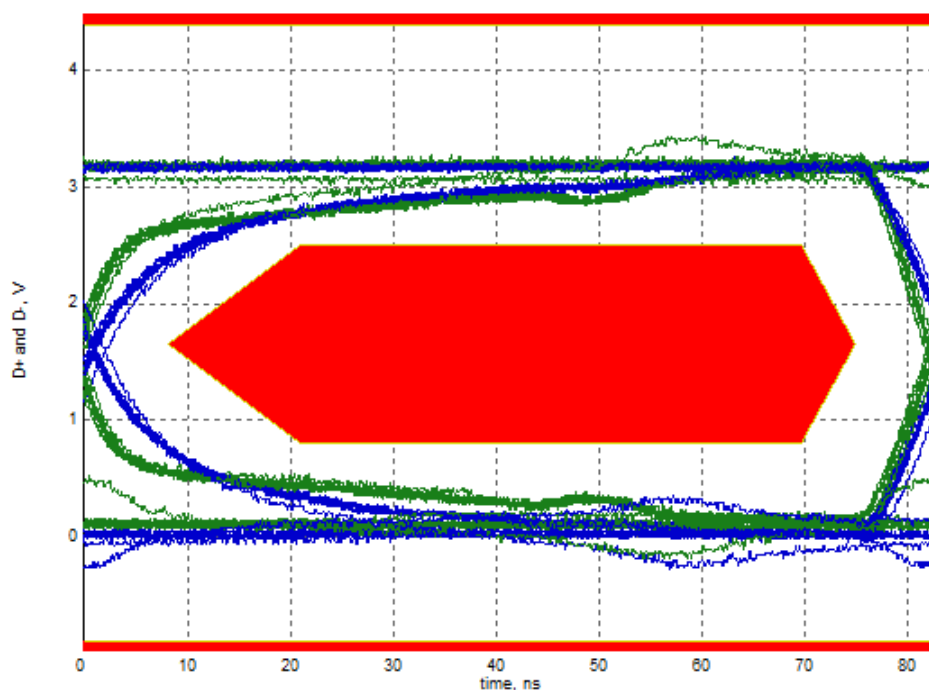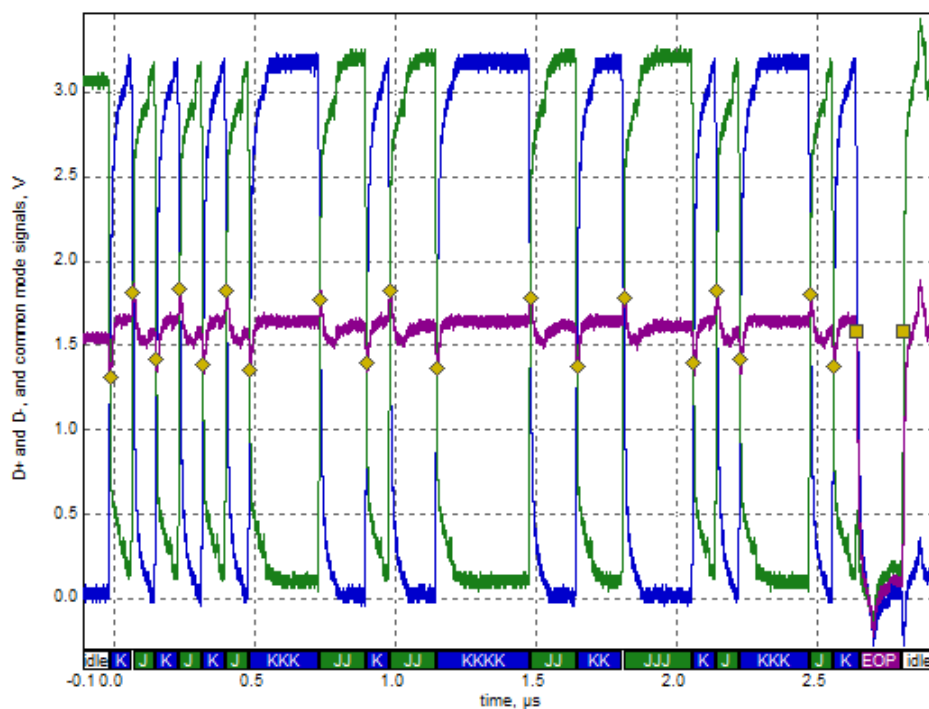Document Number：AR-TRL011413

2. Full Speed Downstream Signal Quality: Pass

- Overall result: pass!
- Sync result:
  sync passes
- Signal eye:
  eye passes
- EOP width: 164.46 ns
  EOP width passes
- Measured signaling rate: 11.9976 MHz
  signal rate passes
- Edge Monotonicity: 80 mV
  Monotonic Edge passes
- Crossover voltage range: 1.31 V to 1.84 V, mean crossover 1.58 V
  (first crossover at 1.31 V, 18 other differential crossovers checked)
  crossover voltages pass
- Consecutive jitter range: -625.588 ps to 499.412 ps, RMS jitter 248.401 ps
- Paired JK jitter range: -383.333 ps to 108.333 ps, RMS jitter 171.020 ps
- Paired KJ jitter range: -425.000 ps to 575.000 ps, RMS jitter 367.848 ps
  jitter passes

Additional Information

- Rising Edge Rate: 169.06 V/us (Equivalent risetime = 15.62 ns)
- Falling Edge Rate: 204.38 V/us (Equivalent falltime = 12.92 ns)
- Edge Rate Match: 18.92% (limit +/-10%)

SignalData and Eye

Project ID：EBH-FRC-USB-002
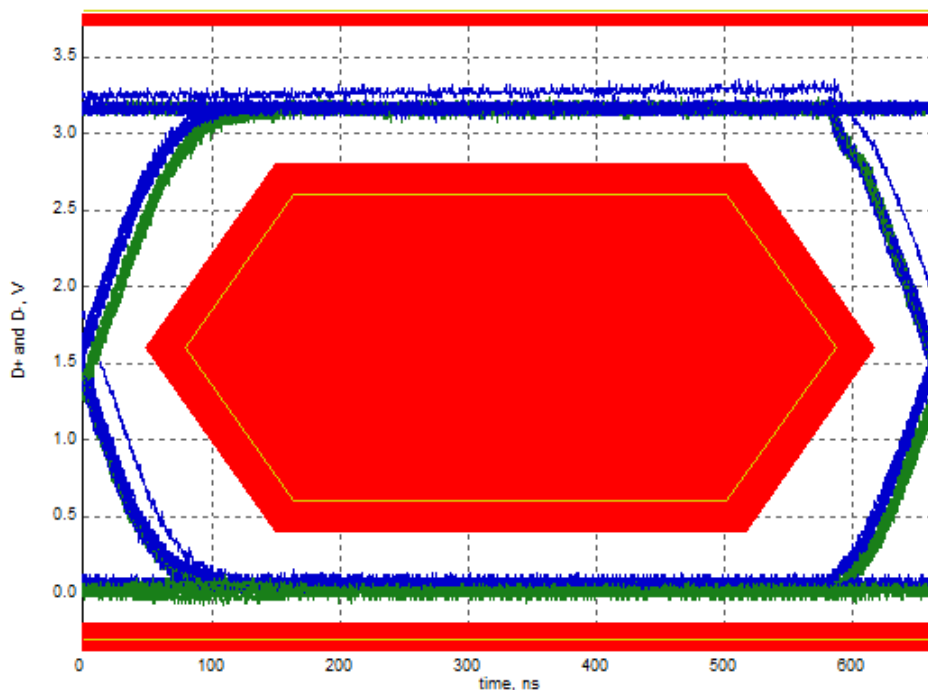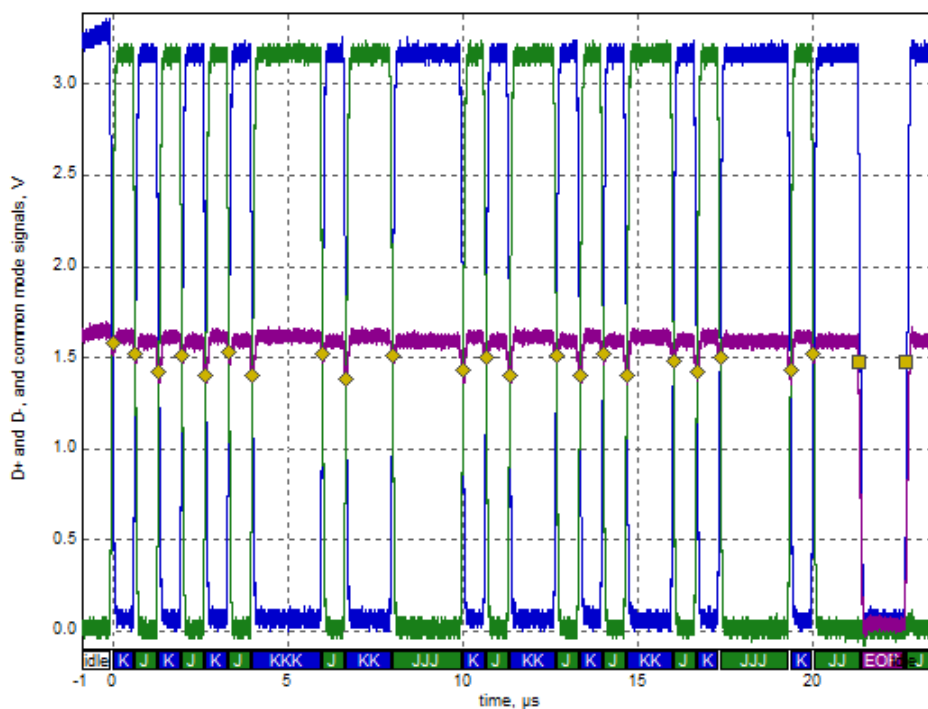Document Number：AR-TRL011413

3. Low Speed Downstream Signal Quality: Pass

- Overall result: pass!
- Sync result:
  sync passes
- Signal eye:
  eye passes
- EOP width: 1.33 us
  EOP width passes
- Measured signaling rate: 1.4995 MHz
  signal rate passes
- Edge Monotonicity: 100 mV
  Monotonic Edge passes
- Crossover voltage range: 1.38 V to 1.58 V, mean crossover 1.47 V
  (first crossover at 1.58 V, 21 other differential crossovers checked)
  crossover voltages pass
- Consecutive jitter range: -5.599 ns to 6.116 ns, RMS jitter 3.484 ns
- Paired JK jitter range: -0.724 ns to 2.657 ns, RMS jitter 1.129 ns
- Paired KJ jitter range: -0.086 ns to 1.210 ns, RMS jitter 0.682 ns
  jitter passes

Additional Information

- Rising Edge Rate: 21.24 V/us (Equivalent risetime = 124.30 ns)
- Falling Edge Rate: 21.93 V/us (Equivalent falltime = 120.38 ns)
- Edge Rate Match: 3.21% (limit +/-20%)

Project ID：EBH-FRC-USB-002
Document Number：AR-TRL011413

SignalData and Eye

Project ID：EBH-FRC-USB-002
Document Number：AR-TRL011413

Test Procedure Reference:
1. USB On-The-Go and Embedded Host Automated Compliance Plan for the On-The-Go & Embedded Host Supplement Revision 2.0, Version 1.2
2. Universal Serial Bus Implementers Forum High-speed System/Motherboard Compliance Test Procedure, Version: 1.4
3. Universal Serial Bus Implementers Forum Full and Low Speed Electrical and Interoperability Compliance Test Procedure, Version: 1.3
4. USB Battery Charging 1.2 Compliance Plan, Revision: 1.1

Notice: Test result is valid only to the original tested device model. The content of test report may not be copied or re-transmitted (except for the entire report) unless it is prior approved by Allion.

Project ID：EBH-FRC-USB-002
Document Number：AR-TRL011413